# BYV32E-200

# Dual rugged ultrafast rectifier diode, 20 A, 200 V

Rev. 04 — 27 February 2009

**Product data sheet** 

# 1. Product profile

### 1.1 General description

Ultrafast dual epitaxial rectifier diode in a SOT78 (TO-220AB) plastic package.

### 1.2 Features and benefits

- High reverse voltage surge capability
- High thermal cycling performance
- Low thermal resistance

- Soft recovery characteristic minimizes power consuming oscillations
- Very low on-state loss

### 1.3 Applications

 Output rectifiers in high-frequency switched-mode power supplies

#### 1.4 Quick reference data

Table 1. Quick reference

iabic i.	Quick reference					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{RRM}$	repetitive peak reverse voltage		-	-	200	V
I <sub>O(AV)</sub>	average output current	square-wave pulse; $\delta$ = 0.5; $T_{mb} \le 115$ °C; both diodes conducting; see Figure 1; see Figure 2	-	-	20	A
I <sub>RRM</sub>	repetitive peak reverse current	$t_p = 2 \ \mu s; \ \delta = 0.001$	-	-	0.2	Α
$V_{ESD}$	electrostatic discharge voltage	HBM; C = 250 pF; R = 1.5 $k\Omega$ ; all pins	-	-	8	kV
Dynamic	characteristics					
t <sub>rr</sub>	reverse recovery time	$I_F = 1 \text{ A}$ ; $V_R = 30 \text{ V}$ ; $dI_F/dt = 100 \text{ A/}\mu\text{s}$ ; $T_j = 25 ^{\circ}\text{C}$ ; ramp recovery; see Figure 5	-	20	25	ns
		$I_R$ = 1 A; $I_F$ = 0.5 A; $T_j$ = 25 °C; step recovery; measured at reverse current = 0.25 A; see Figure 6	-	10	20	ns
Static ch	aracteristics					
V <sub>F</sub>	forward voltage	$I_F = 8 \text{ A}$ ; $T_j = 150 \text{ °C}$ ; see Figure 4	-	0.72	0.85	V





# 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	A1	anode 1		
2	K	cathode	mb	A1
3	A2	anode 2		<u> </u>
mb	К	mounting base; cathode	1 2 3	sym125
			SOT78 (TO-220AB; SC-46)	

# 3. Ordering information

Table 3. Ordering information

Type number	Package			
	Name	Description	Version	
BYV32E-200	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78	

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{RRM}$	repetitive peak reverse voltage		-	200	V
$V_{RWM}$	crest working reverse voltage		-	200	V
$V_R$	reverse voltage	DC	-	200	V
I <sub>O(AV)</sub>	average output current	square-wave pulse; $\delta$ = 0.5; $T_{mb} \le$ 115 °C; both diodes conducting; see Figure 1; see Figure 2	-	20	Α
I <sub>FRM</sub>	repetitive peak forward current	$\bar{\delta}$ = 0.5; $t_p$ = 25 $\mu$ s; $T_{mb}$ ≤ 115 °C; per diode	-	20	Α
I <sub>FSM</sub>	non-repetitive peak forward current	$t_p$ = 8.3 ms; sine-wave pulse; $T_{j(init)}$ = 25 °C; per diode	-	137	Α
		$t_p$ = 10 ms; sine-wave pulse; $T_{j(init)}$ = 25 °C; per diode	-	125	А
I <sub>RRM</sub>	repetitive peak reverse current	$\delta = 0.001$ ; $t_p = 2 \mu s$	-	0.2	Α
I <sub>RSM</sub>	non-repetitive peak reverse current	$t_{p} = 100 \ \mu s$	-	0.2	Α
T <sub>stg</sub>	storage temperature		-40	150	°C
Tj	junction temperature		-	150	°C
V <sub>ESD</sub>	electrostatic discharge voltage	HBM; C = 250 pF; R = 1.5 k $\Omega$ ; all pins	-	8	kV

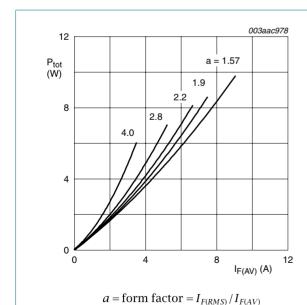
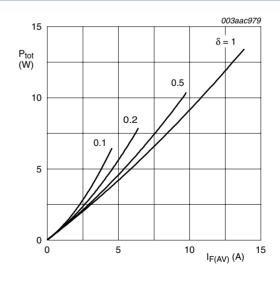


Fig 1. Forward power dissipation as a function of average forward current; sinusoidal waveform; maximum values



 $I_{F(AV)} = I_{F(RMS)} \times \sqrt{\delta}$ 

Fig 2. Forward power dissipation as a function of average forward current; square waveform; maximum values

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### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting	with heatsink compound; both diodes conducting	-	-	1.6	K/W
	base	with heatsink compound; per diode; see Figure 3	-	-	2.4	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient		-	60	-	K/W

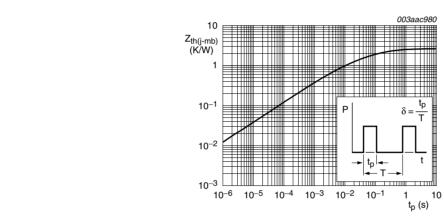
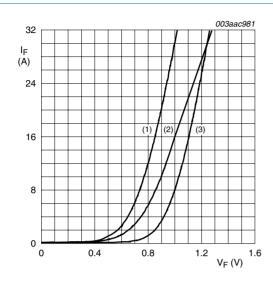


Fig 3. Transient thermal impedance from junction to mounting base as a function of pulse width

### 6. Characteristics

Table 6. Characteristics

Parameter	Conditions	Min	-		
	~ · · · · · · · · · · · · · · · · · · ·	141111	Тур	Max	Unit
aracteristics					
forward voltage	I <sub>F</sub> = 20 A; T <sub>j</sub> = 25 °C	-	1	1.15	V
	$I_F = 8 \text{ A}; T_j = 150 \text{ °C}; \text{ see } \frac{\text{Figure 4}}{}$	-	0.72	0.85	V
reverse current	$V_R = 200 \text{ V}; T_j = 100 \text{ °C}$	-	0.2	0.6	mΑ
	V <sub>R</sub> = 200 V; T <sub>j</sub> = 25 °C	-	6	30	μΑ
characteristics					
recovered charge	$I_F = 2 \text{ A}; V_R = 30 \text{ V}; dI_F/dt = 20 \text{ A/}\mu\text{s}; $ $T_j = 25 ^{\circ}\text{C}$	-	8	12.5	nC
reverse recovery time	$I_F = 1 \text{ A}$ ; $V_R = 30 \text{ V}$ ; $dI_F/dt = 100 \text{ A/}\mu\text{s}$ ; ramp recovery; $T_j = 25 \text{ °C}$ ; see Figure 5	-	20	25	ns
	$I_F = 0.5 \text{ A}$ ; $I_R = 1 \text{ A}$ ; step recovery; measured at reverse current = 0.25 A; $T_j = 25 ^{\circ}\text{C}$ ; see Figure 6	-	10	20	ns
forward recovery voltage	$I_F$ = 1 A; $dI_F/dt$ = 10 A/ $\mu$ s; $T_j$ = 25 °C; see Figure 7	-	-	1	V
	forward voltage  reverse current  characteristics recovered charge  reverse recovery time	$I_F = 20 \text{ A}; T_j = 25 \text{ °C}$ $I_F = 8 \text{ A}; T_j = 150 \text{ °C}; \text{ see } \underline{\text{Figure 4}}$ $V_R = 200 \text{ V}; T_j = 100 \text{ °C}$ $V_R = 200 \text{ V}; T_j = 25$	$\begin{array}{c} \text{forward voltage} & \text{I}_F = 20 \text{ A}; \ T_j = 25 \text{ °C} \\ \text{I}_F = 8 \text{ A}; \ T_j = 150 \text{ °C}; \ \text{see } \underline{\text{Figure 4}} \\ \text{reverse current} & \text{V}_R = 200 \text{ V}; \ T_j = 100 \text{ °C} \\ \text{V}_R = 200 \text{ V}; \ T_j = 25 \text{ °C} \\ \end{array}$ $\begin{array}{c} \text{characteristics} \\ \text{recovered charge} & \text{I}_F = 2 \text{ A}; \ \text{V}_R = 30 \text{ V}; \ \text{dI}_F/\text{dt} = 20 \text{ A/\mu s}; \\ T_j = 25 \text{ °C} \\ \end{array}$ $\begin{array}{c} \text{reverse recovery time} \\ \text{I}_F = 1 \text{ A}; \ \text{V}_R = 30 \text{ V}; \ \text{dI}_F/\text{dt} = 100 \text{ A/\mu s}; \\ \text{ramp recovery}; \ T_j = 25 \text{ °C}; \ \text{see } \underline{\text{Figure 5}} \\ \text{I}_F = 0.5 \text{ A}; \ \text{I}_R = 1 \text{ A}; \ \text{step recovery}; \\ \text{measured at reverse current} = 0.25 \text{ A}; \\ T_j = 25 \text{ °C}; \ \text{see } \underline{\text{Figure 6}} \\ \end{array}$ $\begin{array}{c} \text{forward recovery} \\ \text{I}_F = 1 \text{ A}; \ \text{dI}_F/\text{dt} = 10 \text{ A/\mu s}; \ T_j = 25 \text{ °C}; \ \text{see} \end{array}$	$ \begin{array}{c} \text{forward voltage} & \text{I}_{F} = 20 \text{ A}; T_{j} = 25 \text{ °C} & - & 1 \\ \hline \text{I}_{F} = 8 \text{ A}; T_{j} = 150 \text{ °C}; \text{ see } \underline{\text{Figure 4}} & - & 0.72 \\ \hline \text{reverse current} & V_{R} = 200 \text{ V}; T_{j} = 100 \text{ °C} & - & 0.2 \\ \hline \text{V}_{R} = 200 \text{ V}; T_{j} = 25 \text{ °C} & - & 6 \\ \hline \text{characteristics} & \\ \hline \text{recovered charge} & \text{I}_{F} = 2 \text{ A}; \text{ V}_{R} = 30 \text{ V}; \text{ dI}_{F}/\text{dt} = 20 \text{ A}/\mu\text{s}; & - & 8 \\ \hline \text{T}_{j} = 25 \text{ °C} & \\ \hline \text{reverse recovery time} & \text{I}_{F} = 1 \text{ A}; \text{ V}_{R} = 30 \text{ V}; \text{ dI}_{F}/\text{dt} = 100 \text{ A}/\mu\text{s}; & - & 20 \\ \hline \text{ramp recovery}; \text{ T}_{j} = 25 \text{ °C}; \text{ see } \underline{\text{Figure 5}} & \\ \hline \text{I}_{F} = 0.5 \text{ A}; \text{ I}_{R} = 1 \text{ A}; \text{ step recovery}; & - & 10 \\ \hline \text{measured at reverse current} = 0.25 \text{ A}; \\ \hline \text{T}_{j} = 25 \text{ °C}; \text{ see } \underline{\text{Figure 6}} & \\ \hline \text{forward recovery} & \text{I}_{F} = 1 \text{ A}; \text{ dI}_{F}/\text{dt} = 10 \text{ A}/\mu\text{s}; \text{ T}_{j} = 25 \text{ °C}; \text{ see} & - & - \\ \hline \end{array}$	$ \begin{array}{c} \text{forward voltage} & I_F = 20 \text{ A; } T_j = 25 \text{ °C} & - & 1 & 1.15 \\ \hline I_F = 8 \text{ A; } T_j = 150 \text{ °C; see } \underline{\text{Figure 4}} & - & 0.72 & 0.85 \\ \hline \text{reverse current} & V_R = 200 \text{ V; } T_j = 100 \text{ °C} & - & 0.2 & 0.6 \\ \hline V_R = 200 \text{ V; } T_j = 25 \text{ °C} & - & 6 & 30 \\ \hline \text{characteristics} & \\ \hline \text{recovered charge} & I_F = 2 \text{ A; } V_R = 30 \text{ V; } dI_F/dt = 20 \text{ A/µs; } & - & 8 & 12.5 \\ \hline T_j = 25 \text{ °C} & \\ \hline \text{reverse recovery time} & I_F = 1 \text{ A; } V_R = 30 \text{ V; } dI_F/dt = 100 \text{ A/µs; } & - & 20 & 25 \\ \hline I_F = 0.5 \text{ A; } I_R = 1 \text{ A; step recovery; } & - & 10 & 20 \\ \hline \text{measured at reverse current} = 0.25 \text{ A; } \\ \hline T_j = 25 \text{ °C; see } \underline{\text{Figure 6}} & \\ \hline \text{forward recovery} & I_F = 1 \text{ A; } dI_F/dt = 10 \text{ A/µs; } T_j = 25 \text{ °C; see} & - & - & 1 \\ \hline \end{array}$



- (1)  $T_j = 150$  °C; typical values
- (2)  $T_j = 150$  °C; maximum values
- (3)  $T_j = 25$  °C; maximum values

Fig 4. Forward current as a function of forward voltage

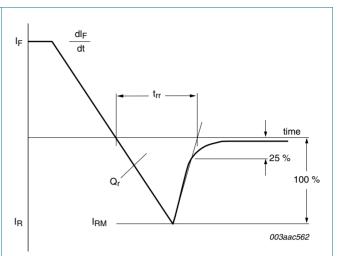


Fig 5. Reverse recovery definitions; ramp recovery

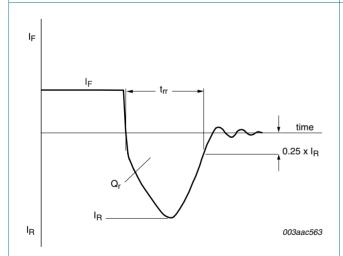


Fig 6. Reverse recovery definitions; step recovery

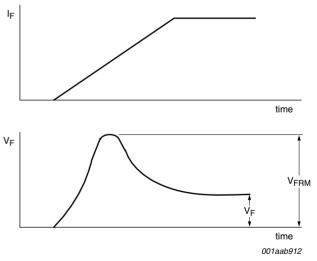


Fig 7. Forward recovery definitions

# 7. Package outline

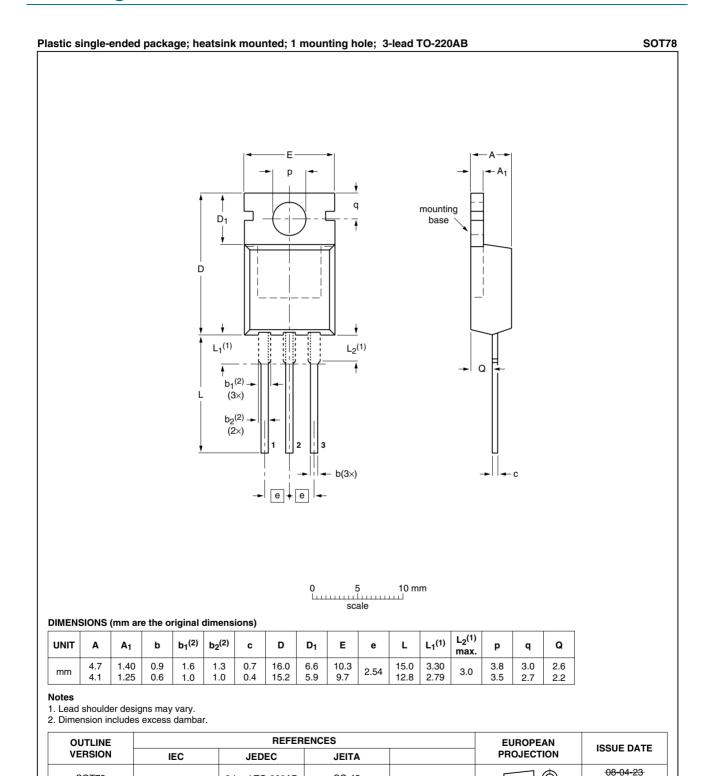


Fig 8. Package outline SOT78 (TO-220AB)

SC-46

3-lead TO-220AB

SOT78

08-06-13



# 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BYV32E-200_4	20090227	Product data sheet	-	BYV32E_SERIES_3
Modifications:		of this data sheet has bee of NXP Semiconductors.	n redesigned to comply w	rith the new identity
	<ul> <li>Legal texts</li> </ul>	have been adapted to the	new company name whe	re appropriate.
	<ul> <li>Package or</li> </ul>	utline updated.		
	<ul> <li>Type numb</li> </ul>	er BYV32E-200 separated	from data sheet BYV32E	SERIES_3
BYV32E_SERIES_3	20010301	Product specification	-	BYV32E_SERIES_2
BYV32E_SERIES_2	19980701	Product specification	-	BYV32EB_SERIES_1
BYV32EB_SERIES_1	19960801	Product specification	-	-



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Document status [1][2]	Product status[3]	Definition
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Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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